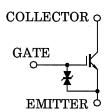
TOSHIBA INSULATED GATE BIPOLAR TRANSISTOR SILICON N CHANNEL IGBT

GT8G121

STROBE FLASH APPLICATIONS

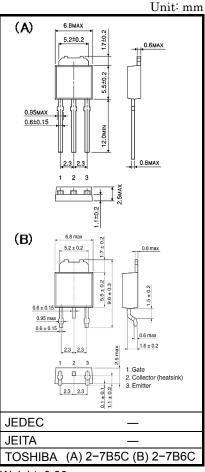
- 4th Generation (Trench Gate Structure)
- Enhancement-Mode
- Low Saturation Voltage
 V_{CE} (sat) = 7 V (Max.) (@I_C = 150 A)
- 4 V Gate Drive



ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Emitter Voltage		V _{CES}	400	V	
Gate-Emitter Voltage	DC	V_{GES}	±6	V	
	Pulse	V_{GES}	±8	V	
Collector Current	DC	IC	8	Α	
Collector Current	1 ms	I _{CP}	150	Α	
Collector Power	Ta = 25°C	PC	1.1	W	
Dissipation	Tc = 25°C	PC	20	W	
Junction Temperature		Tj	150	°C	
Storage Temperature Range		T _{stg}	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in



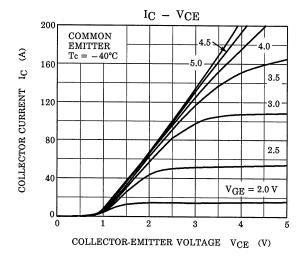
Weight: 0.36 g

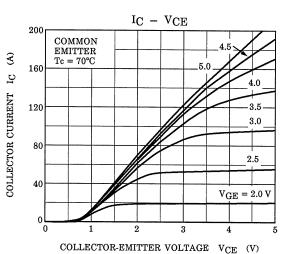
temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

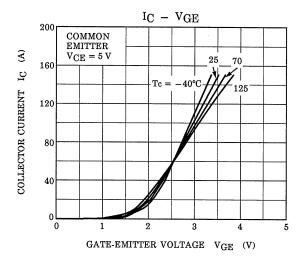
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

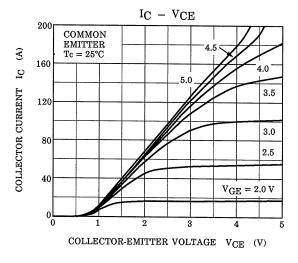
CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Gate Leakage Current		I _{GES}	V _{GE} = 6 V, V _{CE} = 0	_	_	10	μΑ
Collector Cut-off Current		I _{CES}	V _{CE} = 400 V, V _{GE} = 0	_	_	10	μΑ
Gate-Emitter Cut-off Voltage		V _{GE} (OFF)	I _C = 1 mA, V _{CE} = 5 V	0.8	_	1.5	V
Collector-Emitter Saturation Voltage		V _{CE} (sat)	I _C = 150 A, V _{GE} = 4 V (Pulsed)	_	3.5	7	V
Input Capacitance		C _{ies}	V _{CE} = 10 V, V _{GE} = 0, f = 1 MHz	_	3800	_	pF
Switching Time	Rise Time	t _r	$\begin{array}{c c} 4\text{ V} & 51\Omega \\ \text{V}_{\text{IN}}: \text{ t}_{\text{r}} \leq 100 \text{ ns} \\ \text{tf} \leq 100 \text{ ns} \\ \text{Duty cycle} \leq 1\% \end{array} \qquad 300\text{ V}$	_	2.3	_	μs
	Turn-on Time	t _{on}		_	2.5	_	
	Fall Time	t _f		_	1.7	_	
	Turn-off Time	t _{off}		_	2.1	_	
Thermal Resistance		R _{th (j-c)}	_	_	_	6.25	°C / W

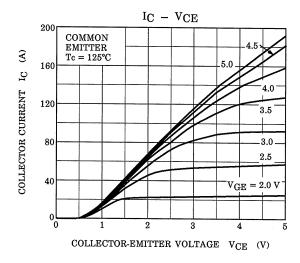
These devices are MOS type. Users should follow proper ESD Handling Procedures. Operating condition of turn-off dv / dt should be lower than 400 V / μ s.

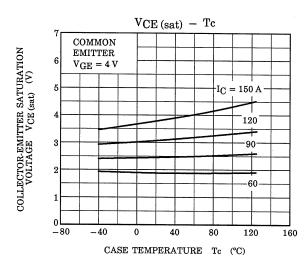


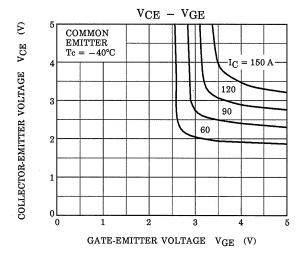


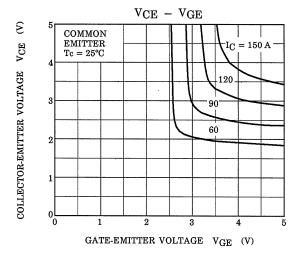


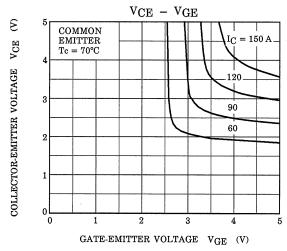


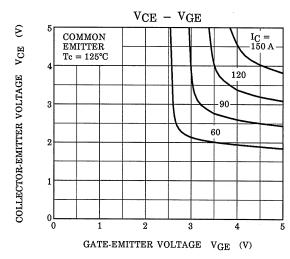


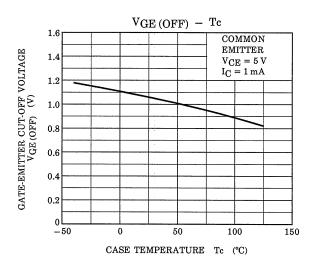


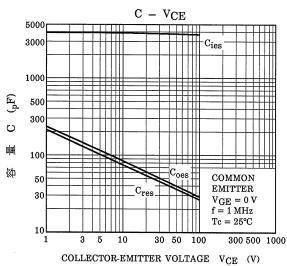


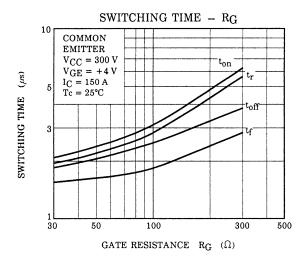


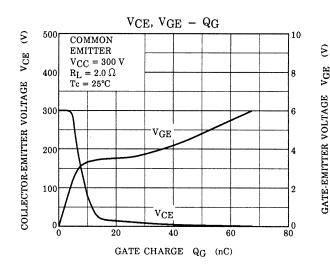


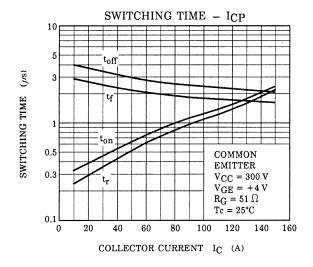


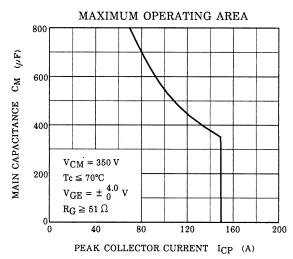


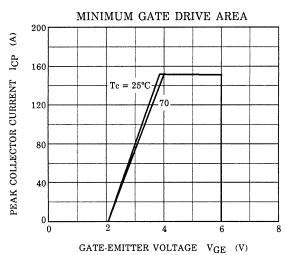












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20070701-EN

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